## 2SD1633

## Silicon NPN triple diffusion planar type darlington

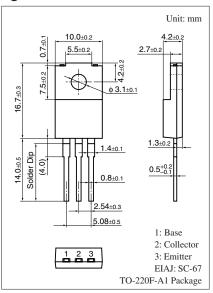
### For voltage switching

#### ■ Features

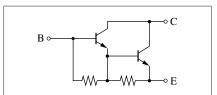
- High-speed switching
- Satisfactory linearity of forward current transfer ratio h<sub>FE</sub>
- Full-pack package which can be installed to the heat sink with one screw

## ■ Absolute Maximum Ratings $T_C = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	100	V	
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	100	V	
Emitter-base voltage (Collector open)	$V_{EBO}$	7	V	
Collector current	$I_C$	5	A	
Peak collector current	$I_{CP}$	8	A	
Base current	$I_B$	0.5	A	
Collector power dissipation	P <sub>C</sub>	30	W	
$T_a = 25$ °C		2.0		
Junction temperature	$T_{j}$	150	°C	
Storage temperature	T <sub>stg</sub>	-55 to +150	°C	



#### Internal Connection



## ■ Electrical Characteristics $T_C = 25$ ° $C \pm 3$ °C

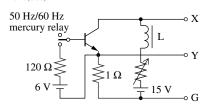
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter sustaining voltage *2	V <sub>CEO(SUS)</sub>	$I_C = 0.2 \text{ A}, L = 25 \text{ mH}$	100			V
Collector-base cutoff current (Emitter open)	$I_{CBO}$	$V_{CB} = 100 \text{ V}, I_E = 0$			100	μΑ
Collector-emitter cut-off current (Base open)	$I_{CEO}$	$V_{CE} = 100 \text{ V}, I_{B} = 0$			100	μΑ
Emitter-base cutoff current (Collector open)	$I_{EBO}$	$V_{EB} = 7 \text{ V}, I_C = 0$			5	mA
Forward current transfer ratio *1	h <sub>FE</sub>	$V_{CE} = 3 \text{ V}, I_{C} = 3 \text{ A}$	1500		15 000	_
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	$I_C = 3 \text{ A}, I_B = 3 \text{ mA}$			1.5	V
Base-emitter saturation voltage	V <sub>BE(sat)</sub>	$I_C = 3 \text{ A}, I_B = 3 \text{ mA}$			2.0	V
Transition frequency	$f_T$	$V_{CE} = 10 \text{ V}, I_{C} = 1 \text{ A}, f = 1 \text{ MHz}$		15		MHz
Turn-on time	t <sub>on</sub>	$I_C = 3 \text{ A}, I_{B1} = 3 \text{ mA}, I_{B2} = -3 \text{ mA}$			3	μs
Storage time	t <sub>stg</sub>	$V_{CC} = 50 \text{ V}$			5	μs
Fall time	t <sub>f</sub>				3	μs

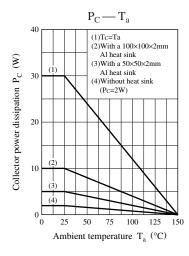
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

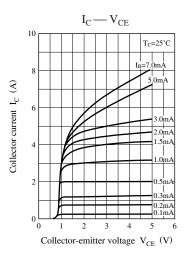
### 2. \*1: Rank classification

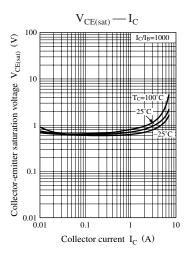
Rank	Q	Р
$h_{\mathrm{FE}}$	1500 to 6000	5 000 to 15 000

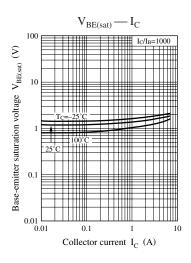
\*2: V<sub>CEO(SUS)</sub> test circuit

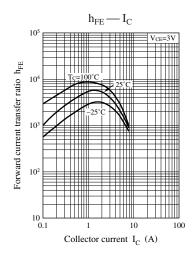


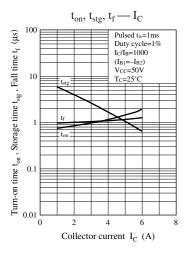


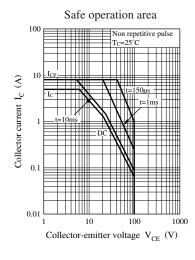


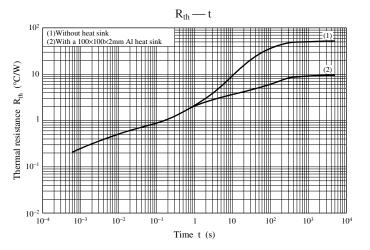












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